



Tektronix

Achieving PCI Express Compliance Faster



Agenda

- PCIe Overview including what's new with Gen4
- PCIe Transmitter Testing
- PCIe Receiver Testing
- Intro to Tektronix's PCIe Tx and Rx Test Solution



PCIe Market Intro

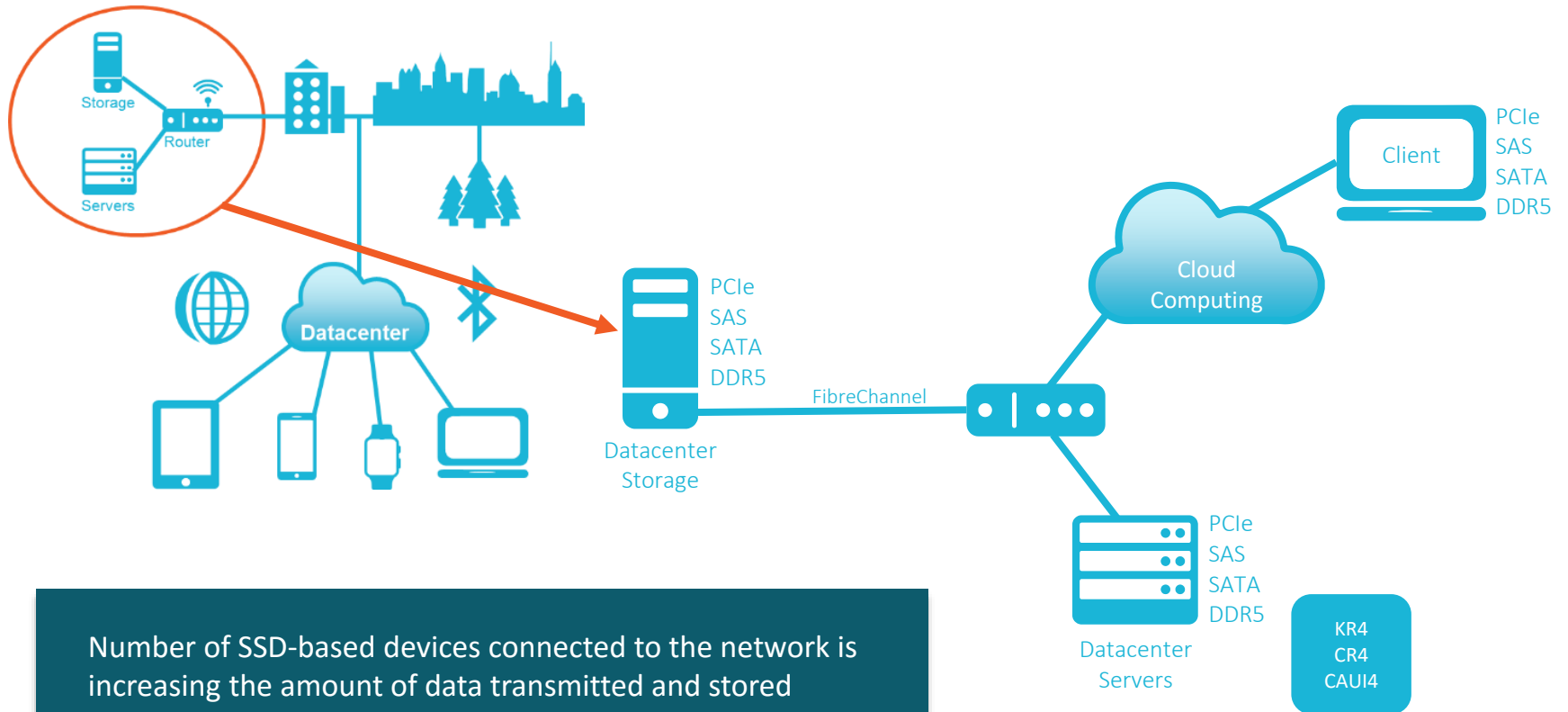


- PCI Express is a **high performance, general purpose I/O interconnect** used in a wide variety of computing & communications products. It has become especially popular for NVME SSD applications
- PCIe is based upon a **point-to-point bus topology** between a root-complex (system/host) & an end-point (add-in card) that supports full-duplex communications.
- The PCIe physical layer consists of:
 - Differential low-voltage signaling
 - **100MHz RefClk is either Common or Separate** (SRIS/SRNS)
 - **Scalable widths:** x1, x2, x4, x8, x12, x16, x32
 - **Scalable speeds:** 2.5GT/s (Gen1), 5GTs (Gen2), 8GT/s (Gen3), 16GT/s (Gen4)
 - **Utilizes connectors**, e.g., CEM, U.2 (SFF-8639), M.2 or soldered directly to PCB
- Specifications are developed & maintained by the **PCI-SIG**, a consortium of >900 companies.



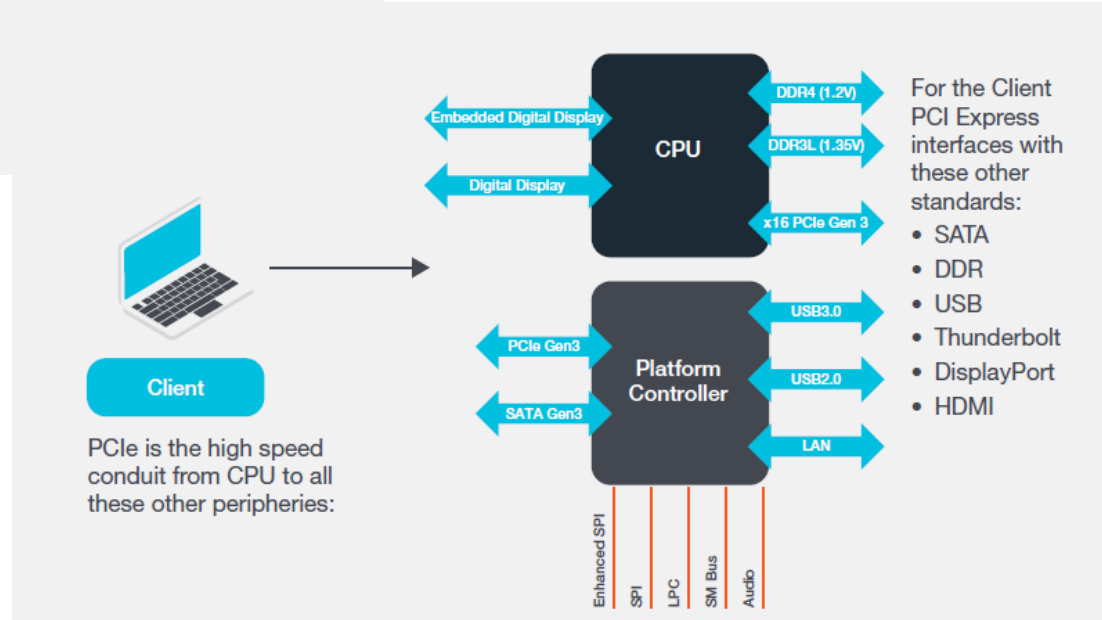
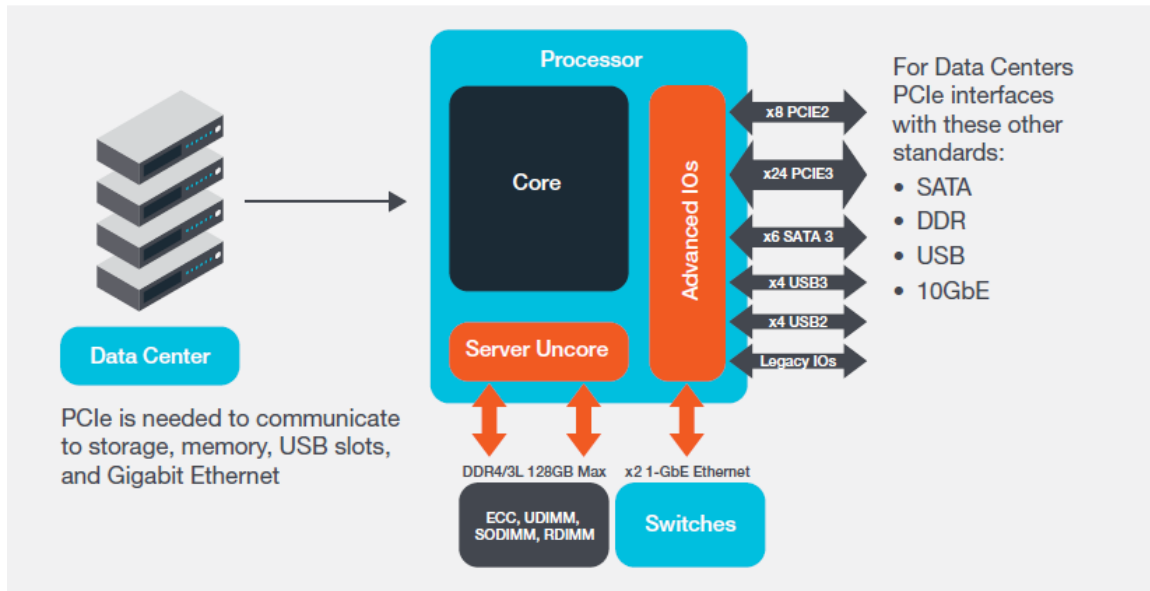
Technology Overview

BIG DATA, IOT AND ANALYTICS DRIVING NEED FOR COMPUTE POWER, STORAGE CAPACITY, AND NETWORK BANDWIDTH



PCI Express Overview

Architecture and Neighboring Technologies

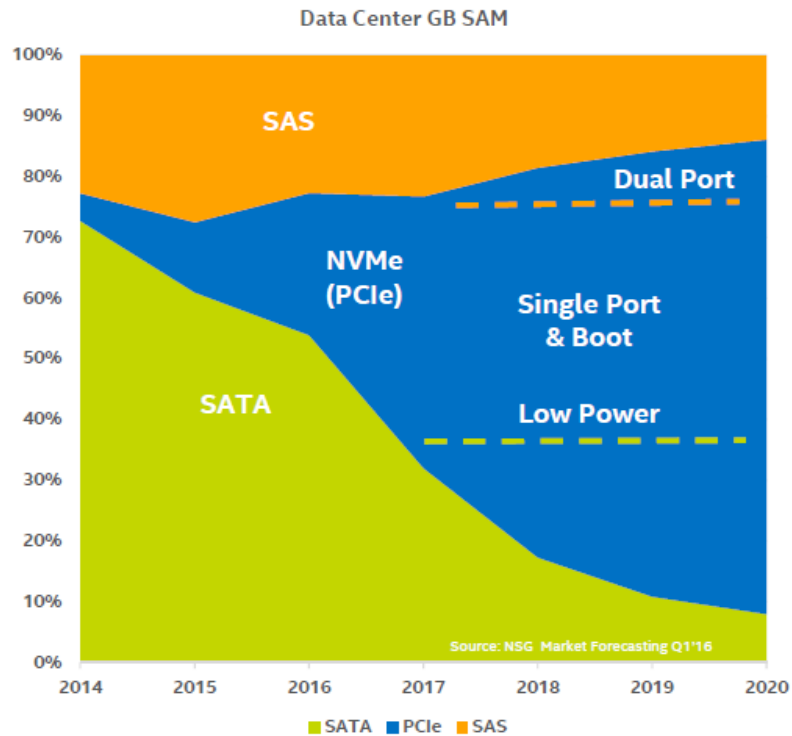


PCI Express is emerging as the primary, high-performance storage bus and SSD Interface



PCIe SSD Forecasted to Lead in Datacenter

EXPECTED TO OVERTAKE SAS IN 2017 & SATA IN 2018



Source: Q1'16 Intel NSG Market Forecasting

- PCI Express (PCIe) projected as leading SSD interface in DC by 2017
- PCIe bandwidth is significantly higher than SAS or SATA
- NVM Express (NVMe--SW interface) has lower latency than SAS or SATA
- Increasing focus on *scalability* using protocol-driven dynamic cloud management and virtual storage--decreasing CPU overhead and improving performance

PCIe Compliance Testing

PCIe COMPLIANCE TESTING FOR INTEROPERABILITY

- PCIE holds regular compliance workshops/plugfests to certify individual devices' compliance and interoperability, typically 4x/yr
- Vendors who desire to be on PCI-SIG Integrator's List plan to attend PCI-SIG workshops where they must pass all four electrical tests & 80% of interoperability tests
- These vendors look at tests and test equipment and assume that if they buy & use the same equipment, they will pass the workshop electrical tests

PCIE 3.0 Electrical PHY Compliance Tests

Transmitter Testing

Receiver Jitter Tolerance Testing

Tx/Rx Link Equalization Testing

PLL Loop Bandwidth Testing



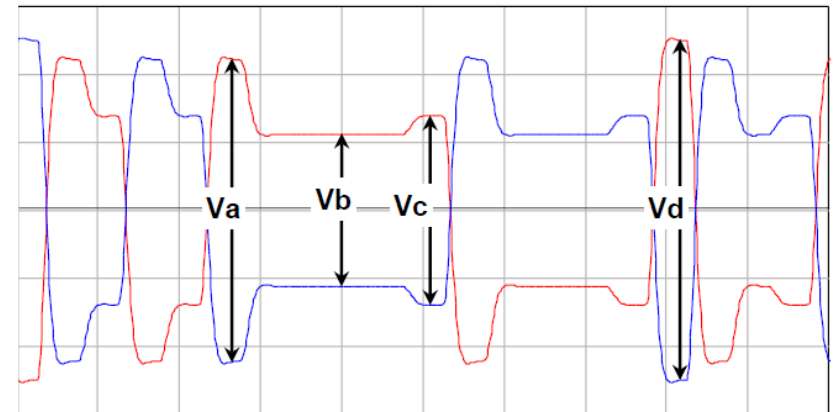
For more details visit PCI Compliance program:

http://www.pcisig.com/specifications/pciexpress/compliance/compliance_library#electrical30

Compliance Equalization Presets

- Once in compliance mode, bursts of 100 MHz clock can be used to cycle through various settings of compliance patterns to perform **automated** jitter, voltage, timing measurements.
- 11 presets for both Gen3 and Gen4 (22 total). All preset values must be supported by DUT.
- For Rx AIC testing, BER < 1E-12 while receiving any valid preset/TXEQ, or < 1E-4 while receiving either P7 or P8

Preset #	Preshoot (dB)	De-emphasis (dB)
P4	0.0	0.0
P1	0.0	-3.5 ± 1 dB
P0	0.0	-6.0 ± 1.5 dB
P9	3.5 ± 1 dB	0.0
P8	3.5 ± 1 dB	-3.5 ± 1 dB
P7	3.5 ± 1 dB	-6.0 ± 1.5 dB
P5	1.9 ± 1 dB	0.0
P6	2.5 ± 1 dB	0.0
P3	0.0	-2.5 ± 1 dB
P2	0.0	-4.4 ± 1.5 dB
P10	0.0	Variable ¹



$$\begin{aligned} \text{De-emphasis} &= 20 \log_{10} V_b/V_a \\ \text{Preshoot} &= 20 \log_{10} V_c/V_b \\ \text{Boost} &= 20 \log_{10} V_d/V_b \end{aligned}$$

1. P10 levels are not fixed; its de-emphasis level is a function of the LF level that the Tx advertises during training. P10 is used to test the boost level of the Tx during full swing

PCIe Gen4 Overview

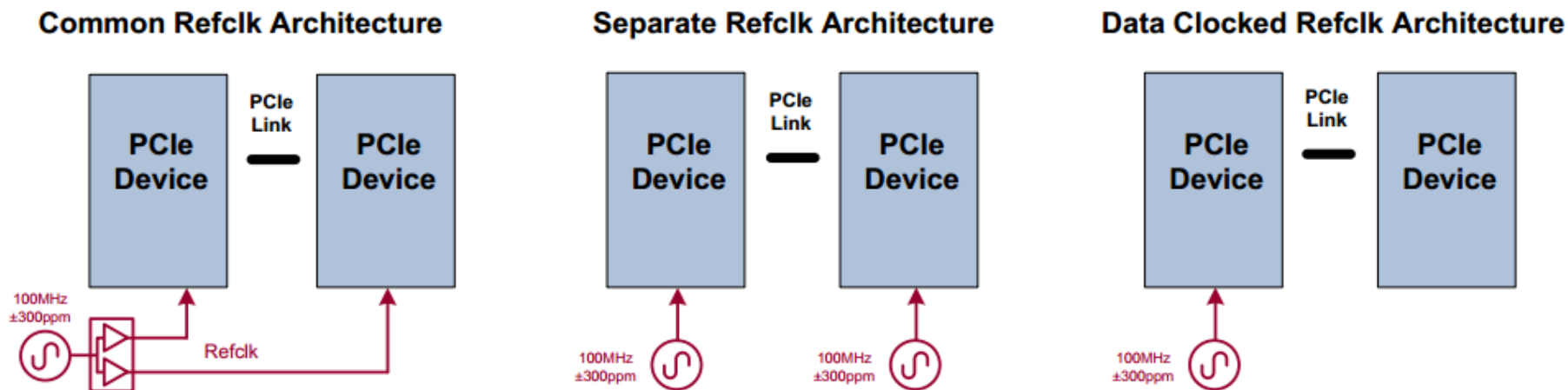
KEY ENHANCEMENTS FROM PCIe GEN3

- Key attributes/requirements of PCIe 4.0
 - 16 GT/s, using scrambling, same as 8 GT/s, no encoding change
 - Reduction in RJ (random jitter) from 3ps (PCIe3) to ~1ps (PCIe4) [PCIe Base Spec, Table 9.8]
 - Maintains backward compatibility w/ PCIe installed base of devices
 - Gen4 connector enhanced electrically
 - Behavioral Rx EQ data rate dependent
 - Limited channel: ~12" for 1 connector (including 4" AIC); requires use of repeater (both redriver & retimer) for longer channels and/or 2nd connector
 - New 'SRIS' independent RefClk modes
 - SRNS – Separate RefClk Independent with No SSC Architecture
 - SRIS – Separate RefClk Independent with SSC Architecture
 - New Rx Lane Margining feature measures EH/EW margin at end of channel
 - Eye height for Gen4 reduced to 15mVpp
- Rev 0.9 Base spec draft to be finalized in Q1 2017
- Gen4 CEM Spec currently at released at rev 0.5, draft 0.7 in process



PCIe RefClk Architectures

- PCIe standard specifies a 100 MHz clock (Refclk) with greater than ± 300 ppm frequency stability at both the transmitting and receiving devices and support for three distinct clocking architectures:



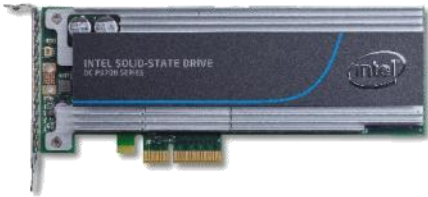
- **Common** – most popular, supports SSC; same clock must be connected to all devices while maintaining skew ≤ 12 ns between devices
- **Separate/independent** – used for cabled applications; SSC not recommended unless both clocks synchronized to a common source
- **Data Clocked** – simplest to implement, but not very common

“Selecting the Optimum PCI Express Clock Source”,
Figure 3 page 3, Silicon Laboratories, Inc.



PCI Express Form Factors

CEM
Add-In-Card
(AIC)



U.2
(SFF-8639)



U.2-to-CEM Adapter



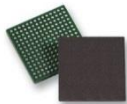
M.2



M.2-to-CEM Adapter

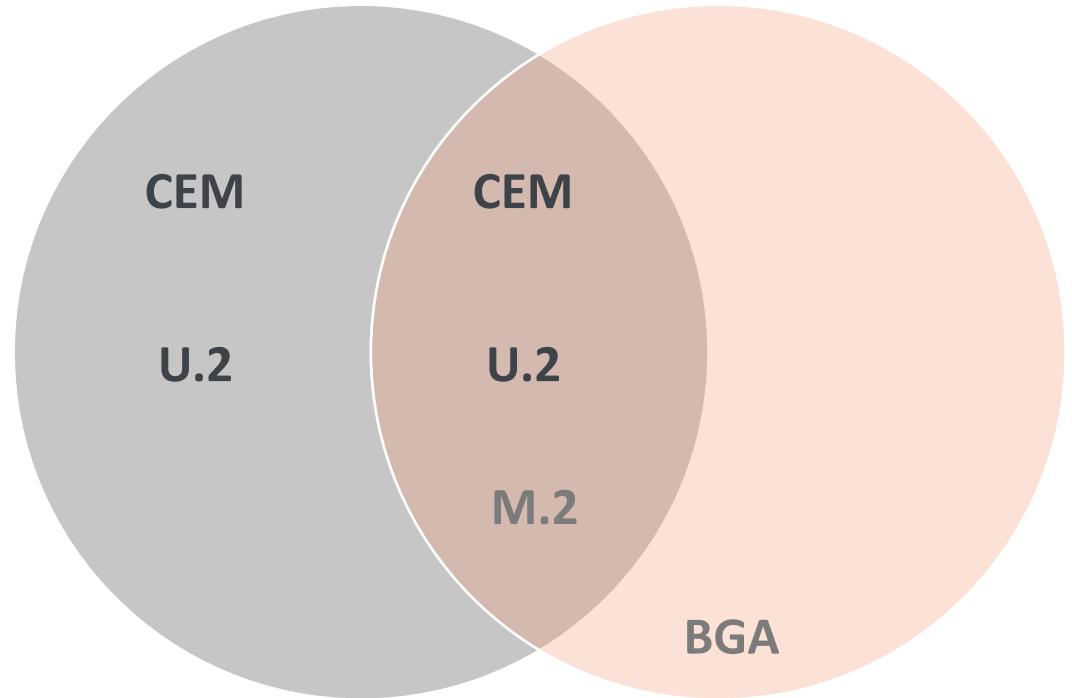


BGA
(Embedded)



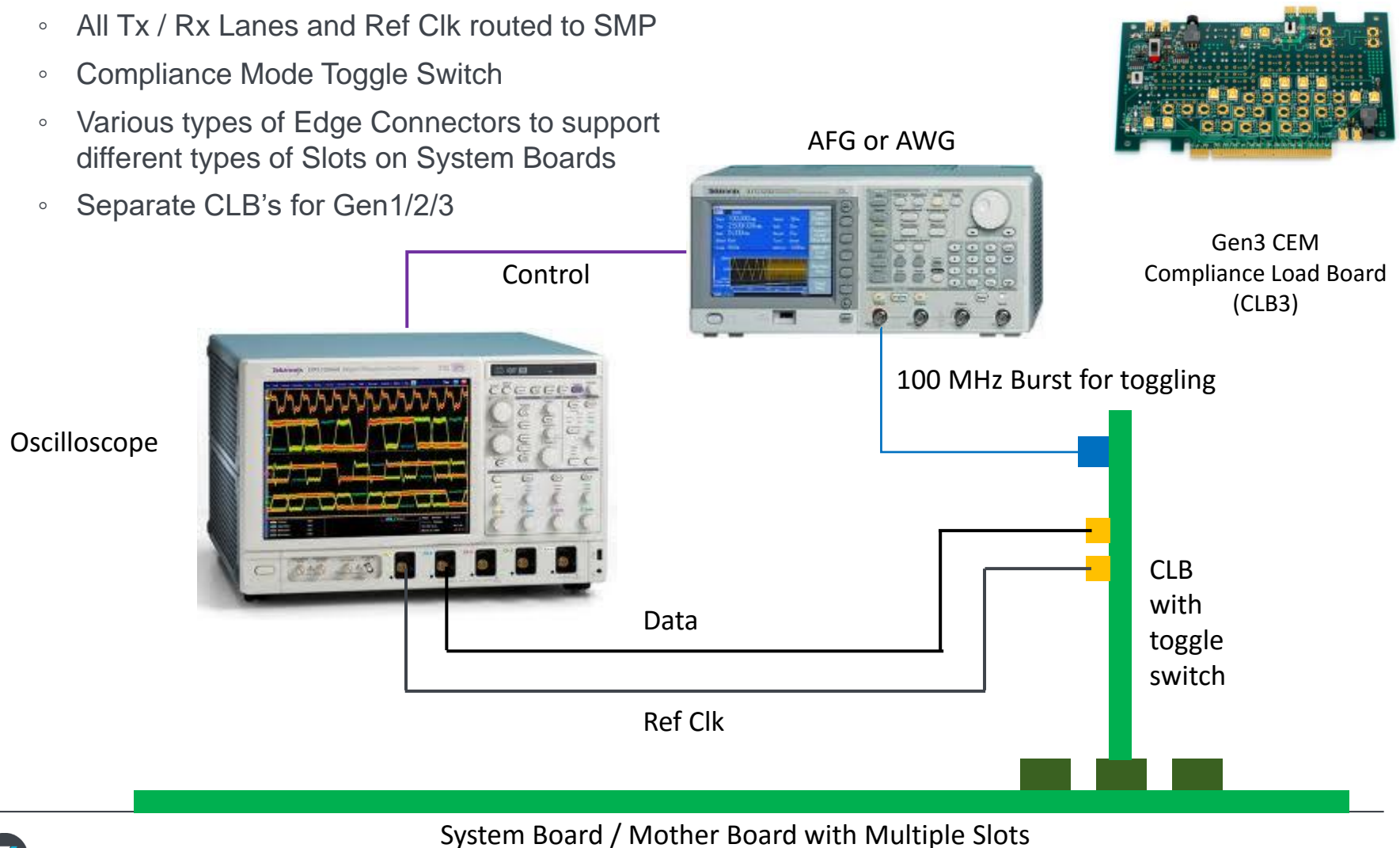
Data Center

Client



Automated DUT Control with Fixtures

- Compliance Load Board (CLB)
 - Used for testing System Boards
 - All Tx / Rx Lanes and Ref Clk routed to SMP
 - Compliance Mode Toggle Switch
 - Various types of Edge Connectors to support different types of Slots on System Boards
 - Separate CLB's for Gen1/2/3



Add-In Card Test Fixture

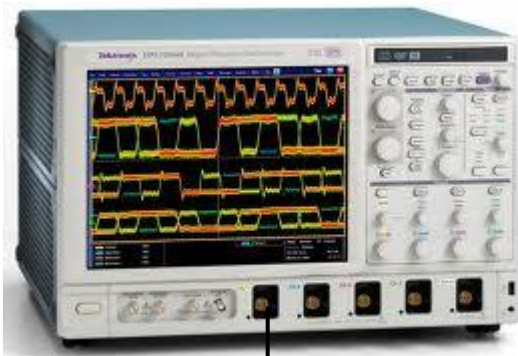
- Compliance Base Board (CBB)
 - Used for Testing Add-In cards
 - All Tx / Rx Lanes are routed to SMP
 - Compliance Mode Toggle Switch
 - Low Jitter Clean Reference Clock
 - Separate CBB for Gen 1/2/3



Gen3 CEM
Compliance Base Board
(CBB3)



Gen3 U.2
Compliance Base Board
(CBB3)



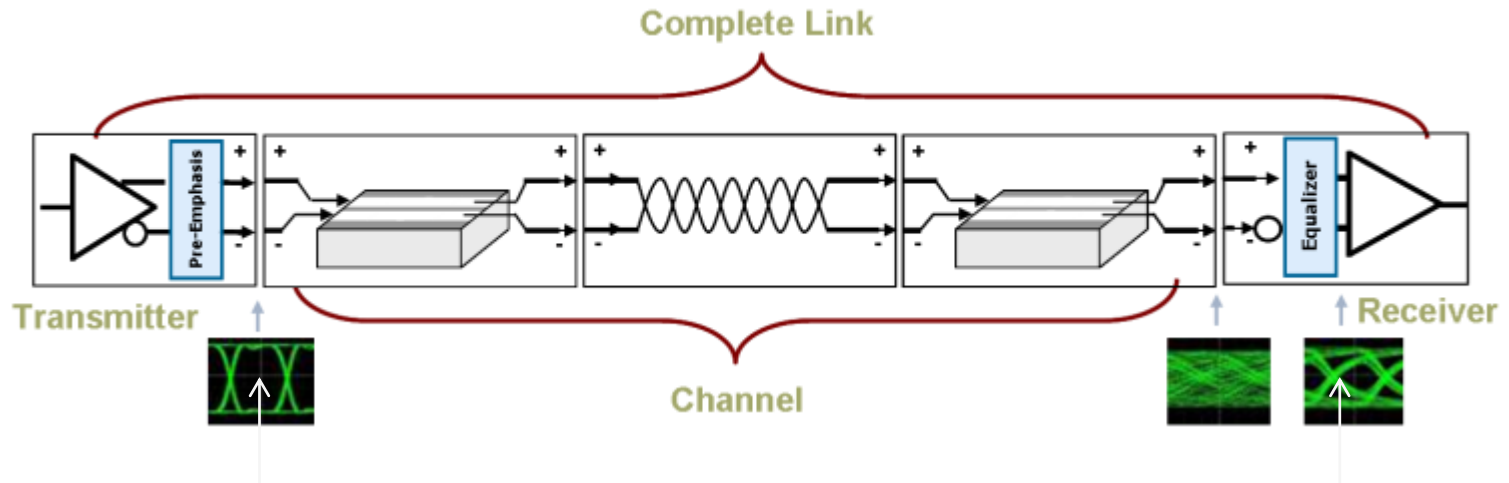
Data

Add-In
Card

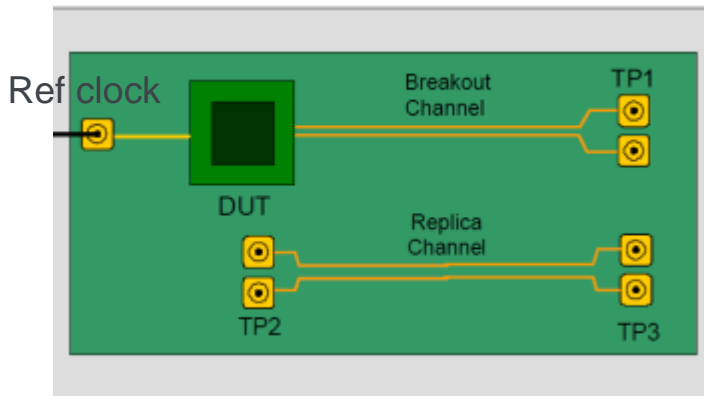
CBB with Multiple Slots of different widths and toggle switch

Form Factor Overview

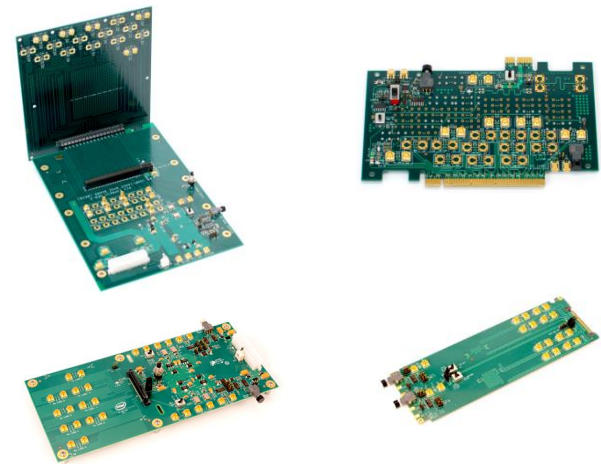
PCIe BASE vs FORM FACTOR (CEM / U.2)



Measure for Base



Measure for CEM & U.2

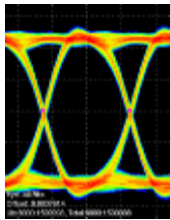


Measuring the signal at the point of interest

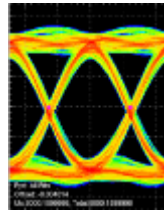
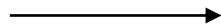
Base Spec Tx Testing

SILICON LEVEL

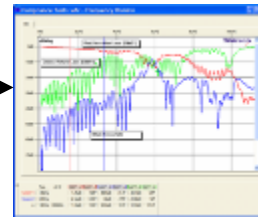
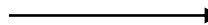
- Base Specification Measurements are defined at the pins of the transmitter
- Signal access at the pins is often not possible
- De-embedding is required to see what the signal looks like at the pins of the TX, without the added effects of the channel
- S-Parameters are acquired on the replica channel
- Measurement at TX pins can also be enabled by high fidelity probes, eg P7700



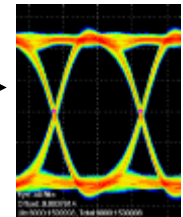
Signal at Tx Pins



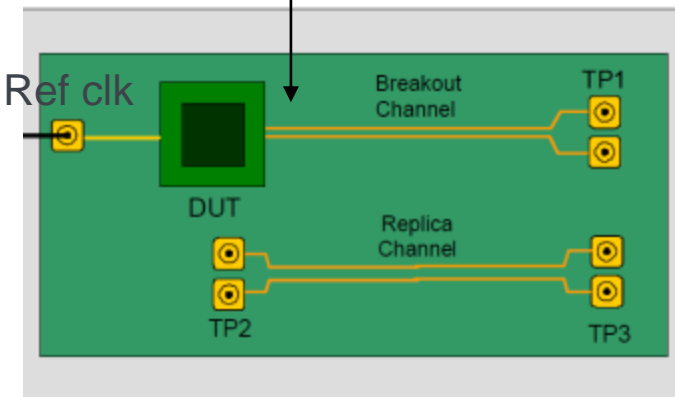
Measured Signal at TP1



De-embed using S-Parameters



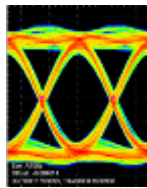
Signal with Channel Effects Removed



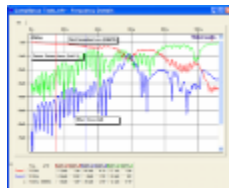
CEM & U.2 Spec Tx Testing

SYSTEM & ADD-IN CARD

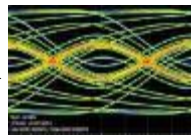
- CEM Specification Measurements are defined at the slicer of a receiver
- Signal access is not possible
- Embedding of the compliance channel and package, as well as application of the behavioral equalizer is required
- SigTest or custom software like DPOJET will perform the embedding and calculate measurements



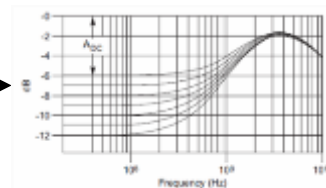
Signal Acquired
from Compliance
Board



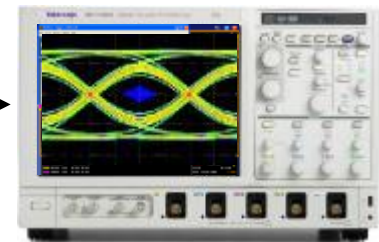
Embed Compliance
Channel and Package



Closed Eye due to
the Channel



Apply CTLE + DFE



Open Eye for
Measurements

New Challenges in Rx Testing

PHY AND PROTOCOL-AWARE TEST AND DEBUG

Requires Protocol Awareness

1. Putting device into loopback
2. Performing link equalization

Need Automated Solutions for Gen3 and Gen4 Standards

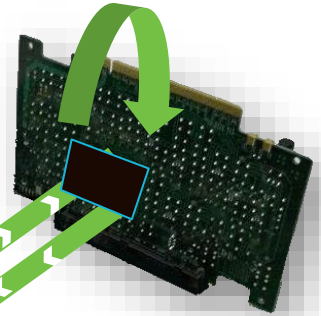
3. Easy setup
4. Auto calibration of stresses.
5. Making accurate and repeatable measurements

Go beyond compliance

6. Root-causing factors leading to bit-error or link training problems

Pattern Generator with Stress

Error Counter



ERROR BIT LOCATION	EXPECTED BIT
200,457	0
1,247,356	1
1,447,890	0
3,885,245	0
4,001,876	1
8,233,191	0
...	

New Challenges in Rx Testing

PHY AND PROTOCOL-AWARE TEST AND DEBUG

- Repeater IC's increasingly important to improve signal integrity
 - Increasingly lossy channels and increasing data rates (**-28dB** for PCIe Gen4 CEM)
 - **Need to open eye at end of the channel!**
 - Different types of repeater IC's used:
 - *Redriver*—no clock-data recovery (CDR)
 - *Clock-synchronous retimer*—has CDR, clocks data to recovered clock
 - *Clock-compensating retimer*—has CDR, clocks data to ref clock
 - Repeaters include some combination of SERDES, CDR, and CTLE/DFE equalization capability to open eye after lossy channel
 - *CTLE* = continuous time linear equalization
 - *DFE* = decision feedback equalizer

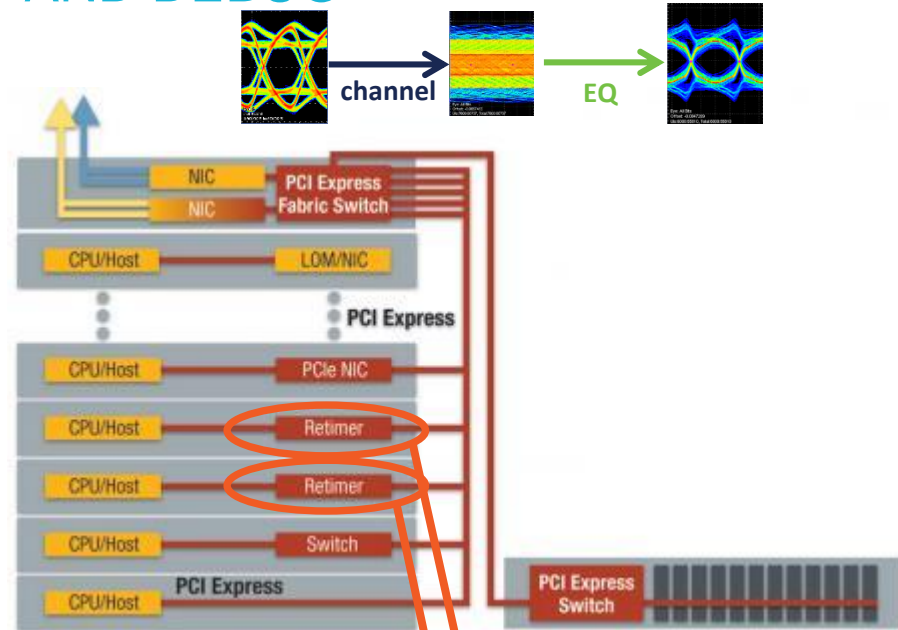


Diagram courtesy of *Fabric of the Cloud*, ITC Magazine May 2012

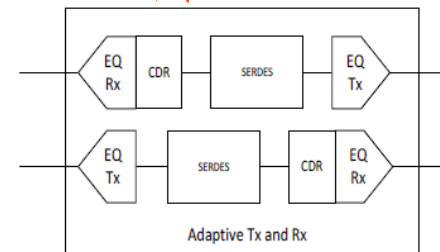
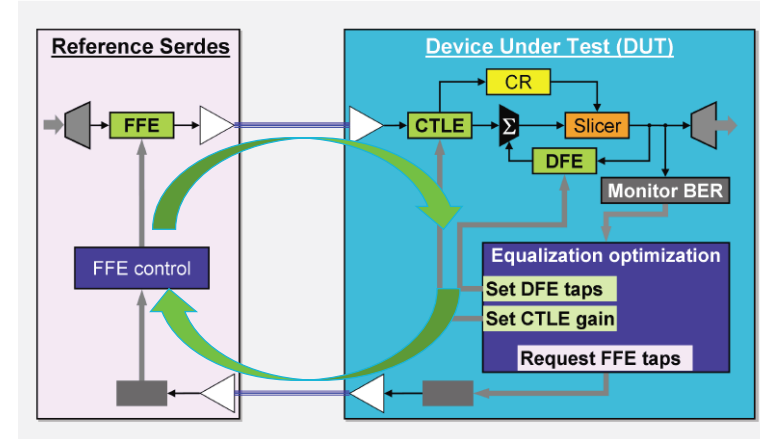


Diagram courtesy of *Proposed Concepts for SPL-5 to improve design flexibility and connectivity*, Microsemi, Nov 2016

New Challenges in Rx Testing

PHY AND PROTOCOL-AWARE TEST AND DEBUG

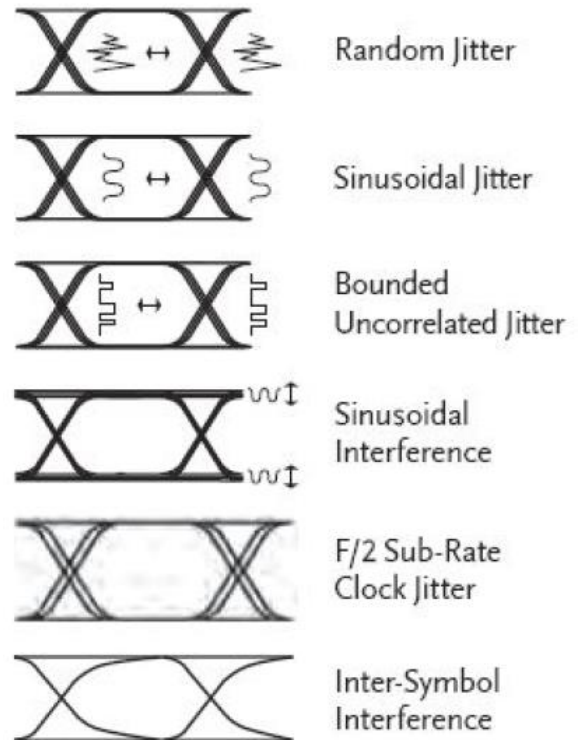
- Entire link (including repeaters) requires link training capability.
 - Adaptive, optimizing equalization that requires coordination of Tx and Rx for each link at power up and recovery
 - Precise orchestration of FFE, CTLE, CR, slicer, and DFE functionality is essential,
 - Data stream/protocol management (scrambling, sequencing, encoding test patterns)
- NRZ (non-return to zero) symbol decoders/bit slicers with 15mVpp sensitivity.
- Some standards (eg SAS4) also use forward error correction (FEC) to relax bit error rate (BER) requirements, but also complicate measurements.



New Challenges in Rx Testing

PHY AND PROTOCOL-AWARE TEST AND DEBUG

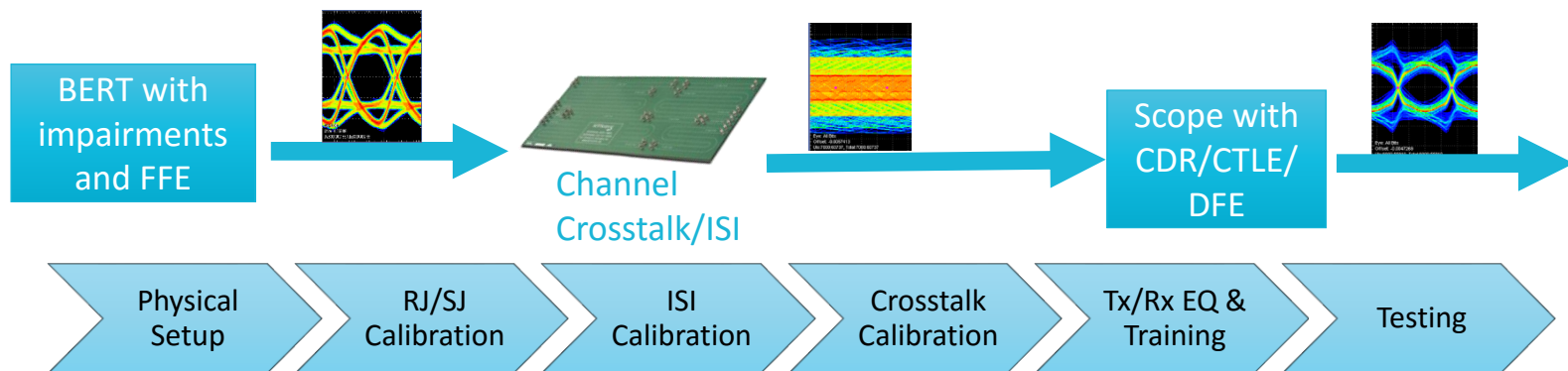
- Receiver margin testing requires calibrated insertion of various stresses for worst-case compliance testing:
 - Inter-Symbol Interference (ISI)
 - Random Jitter (RJ),
 - Common-Mode/Differential Mode Interference (CMI/DMI)
- Reference receiver models assist in calibrating compliance test conditions (eg Seasim/SigTest):
 - Models include the transmitted signal, applied stresses, and channel response to the receiver input pins



How to Address new Gen4 Challenges?

PHY AND PROTOCOL-AWARE TEST AND DEBUG

- Need fully integrated test system, including HW and SW solutions
 - Reliably put device under test into loopback mode
 - Facilitate link equalization training to optimize the channel, including built-in TXEQ and RXEQ optimization
 - Calibrate and sweep full suite of impairments (ISI, RJ, DMSI, CMI)
 - Debug DUT-specific problems with BER, FEC, and link training
- Solution must cover multiple standards (eg SATA, SAS, PCIe) and spec generations (eg Gen3, Gen4, etc)

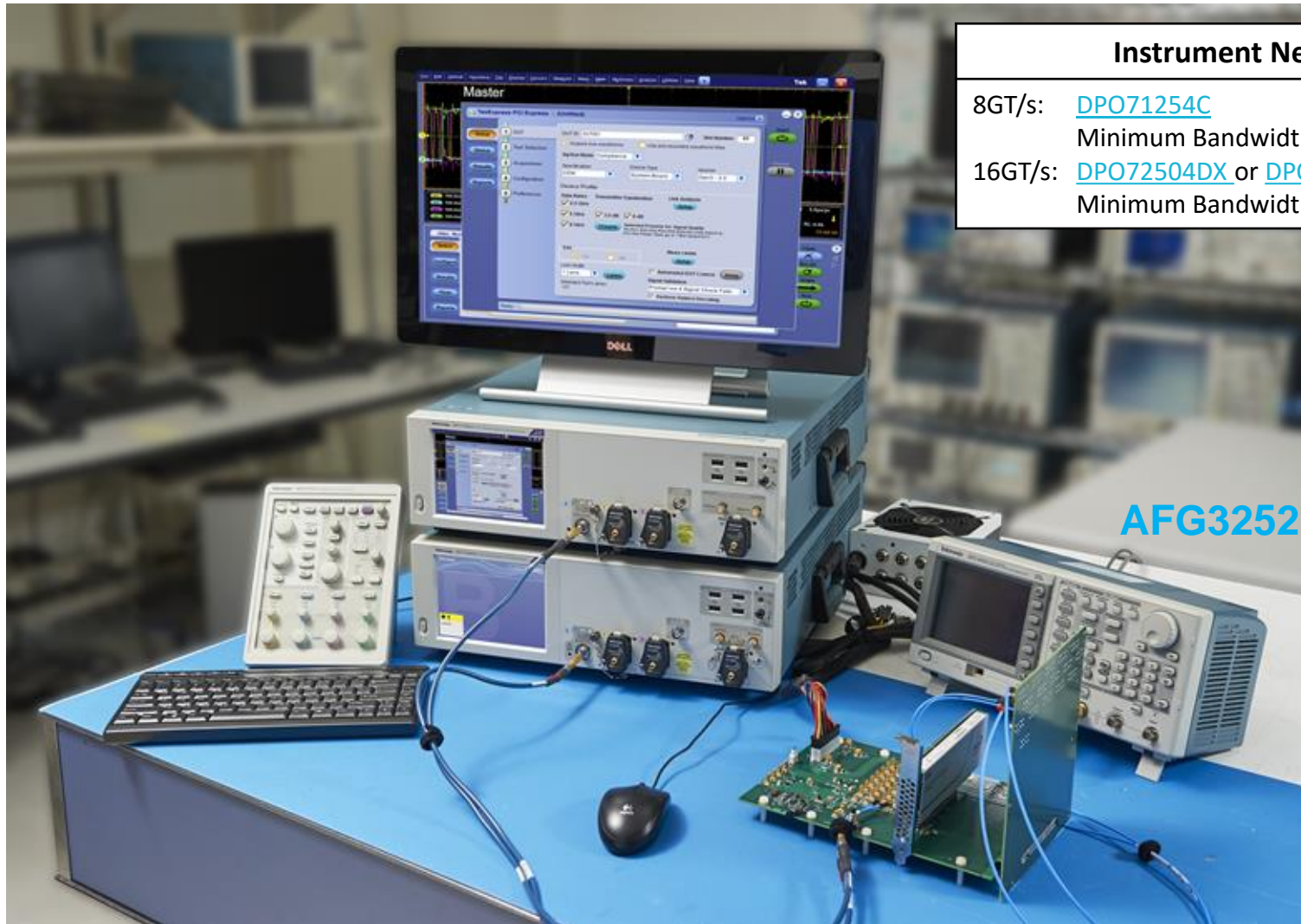


Key Points in PCIe Test and Debug

- PCI Express (PCIe) will become the dominant storage interconnect in 2017.
 - New designs and players, broader customer implementation base, new specs to understand and apply, new compliance participation.
- A majority of PCIe Gen3 designs failed protocol compliance test at the first plugfest.
 - How will you verify protocol compliance on your device?
- Transmitter margin dependent on channel and optimized equalizer settings.
 - How will you verify actual transmitter margin meets design goals?
- Server environments will require repeaters or re-timers, essential for signal transmission over long lossy channels. These IC's double the number of equalization combinations possible.
 - How will you debug and perform interoperability test when repeaters/re-timers are present?
- Receiver lane margining tools will expose device performance and margin.
 - How will you verify actual receiver margin meets design goals?
- Custom high-speed serial interfaces will be used for application specific tasks.
 - How will you test your custom interface and verify operation to design goals?
- Receivers require unique external signal recipes to initiate test mode.
 - How will you establish loopback mode on your device to enable testing?



Tektronix PCIe Tx Solution



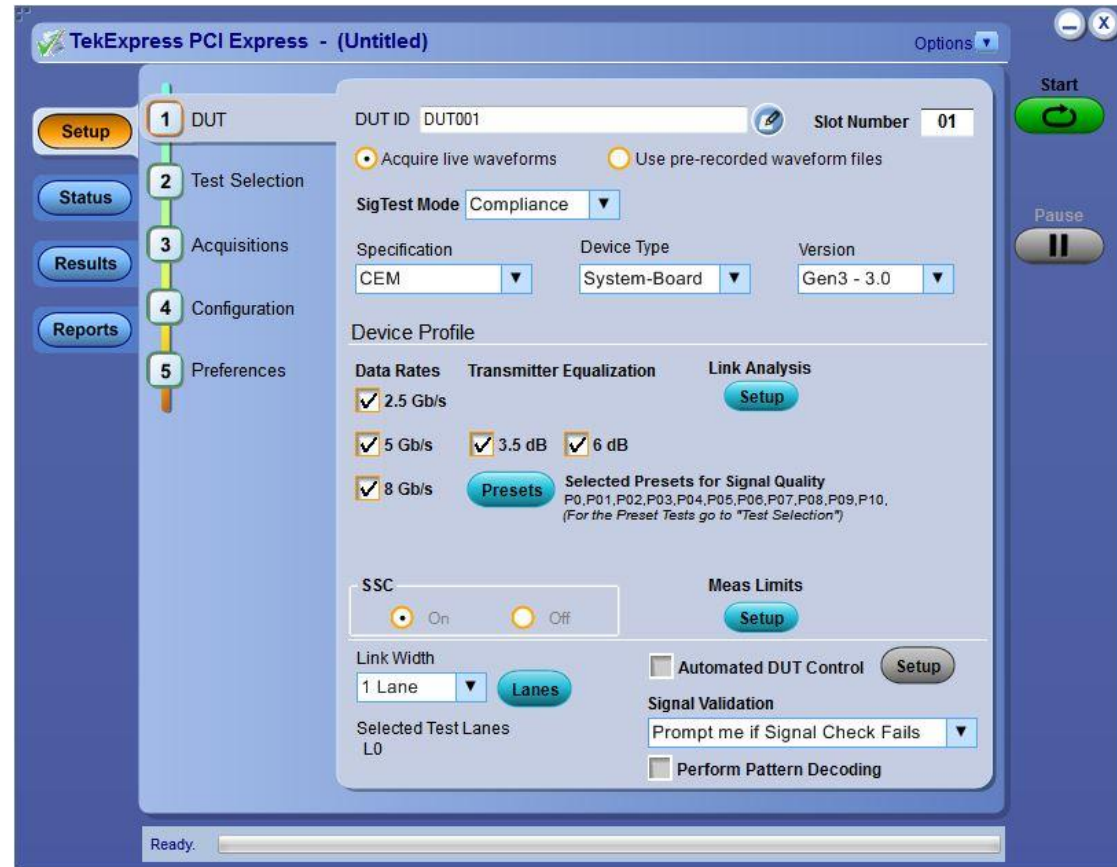
Instrument Needed	
8GT/s:	DPO71254C Minimum Bandwidth: 12.5GHz
16GT/s:	DPO72504DX or DPO73304SX Minimum Bandwidth: 25GHz

AFG3252

TekExpress for PCIe (Opt PCE4)

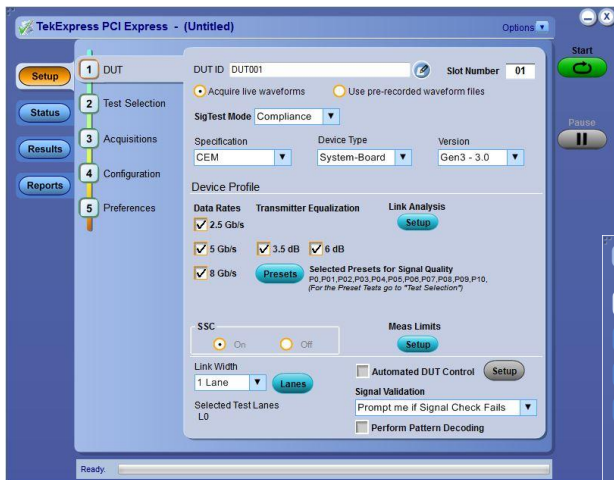
- TekExpress Automation for Tx Compliance with unique features including:

- ✓ Sets up the Scope and DUT for testing
- ✓ Toggles thru and verifies the different Presets and Bit Rates
- ✓ Tests multiple slots and lanes
- ✓ Acquires the data
- ✓ Processed with PCI-SIG SigTest
- ✓ Provides custom reporting

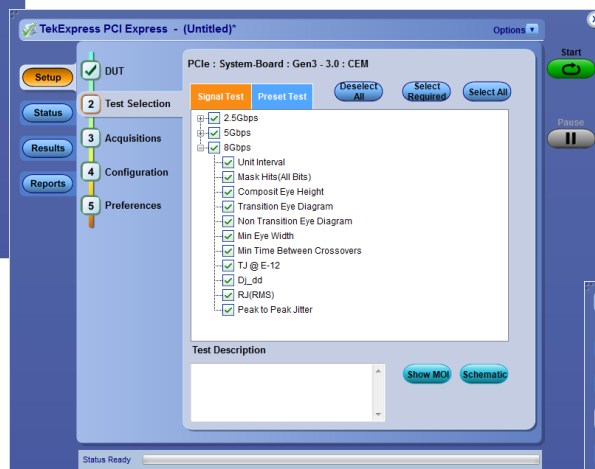


TekExpress PCIe Automated Test

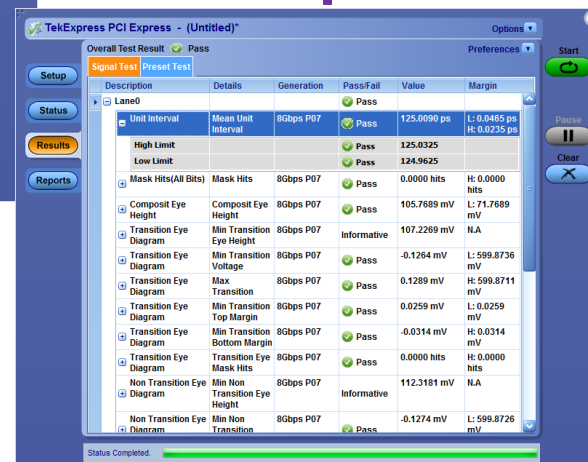
Setup



Test



Reports



Run Analysis on Live or Pre-Recorded Data

Type of test / device selection

Test selection

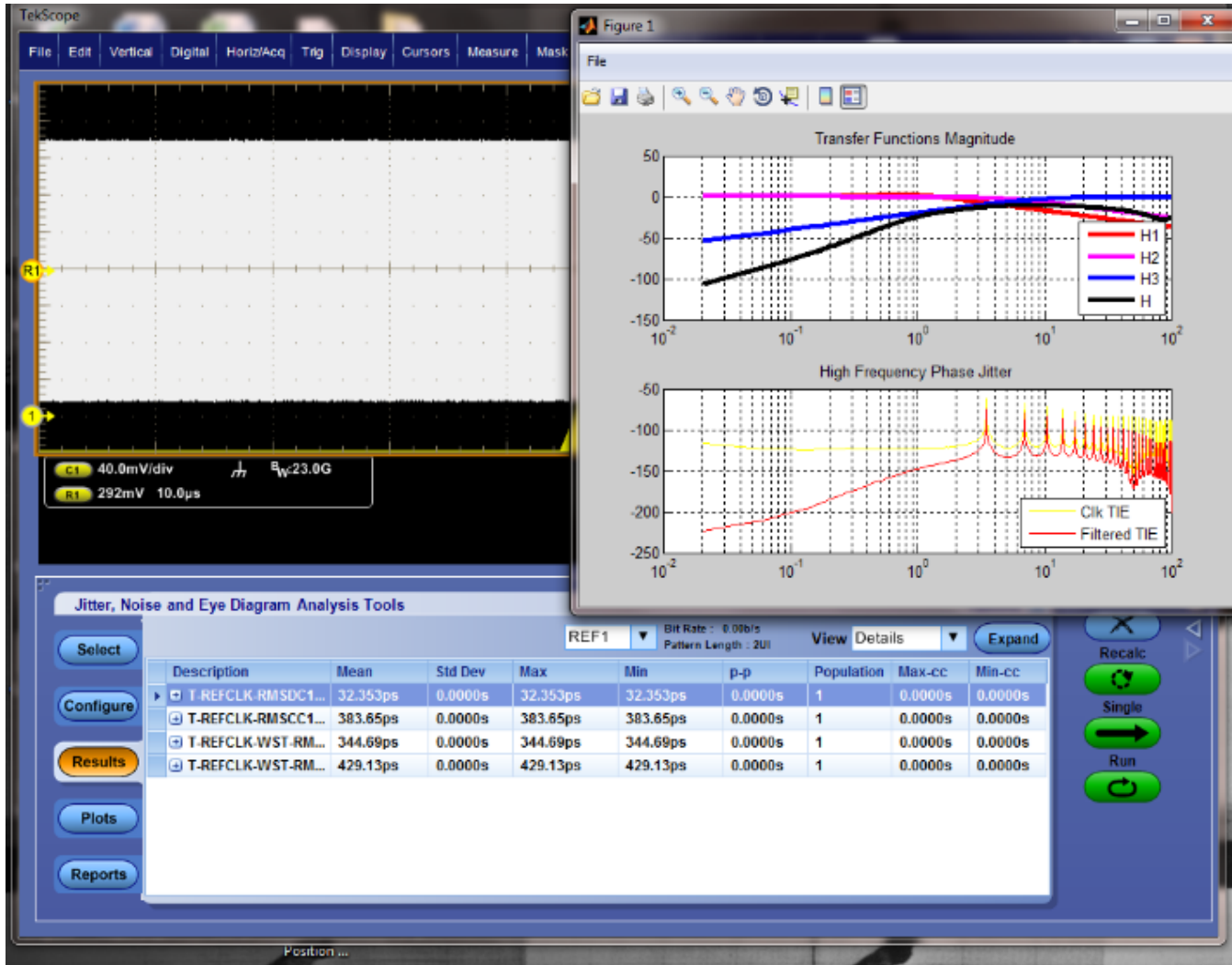
Automate DUT control

Test Selection

Standards-compliant pass/fail reports

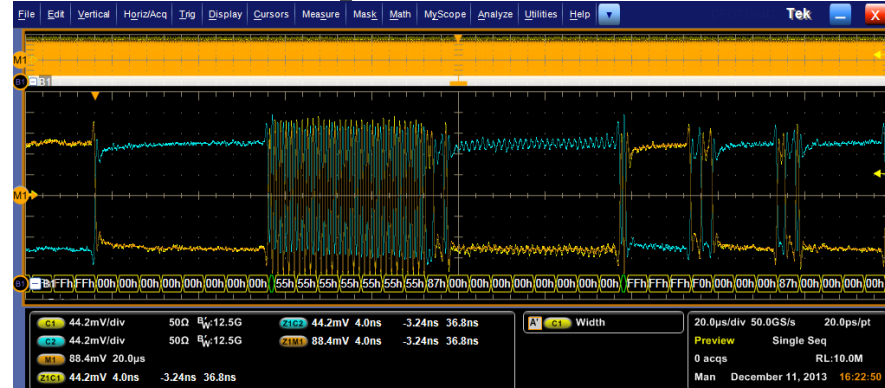


DPOJet for PCIe Gen1-4 RefClk MEASUREMENTS



PCIe Decoder (Opt SR-PCIe)

- Provides link layer decoding
- Decodes and displays PCIe data using characters and names that are familiar from the standard, such as:
 - SKP
 - Electrical Idle
 - EIEOS
- Easily configured through “Bus Setup” under “Vertical” menu with a variety of user-adjustable settings
- Results table shows time-correlated listing of events time-correlated with waveform view
- Integrated search with marks



Results Table

Index	Start Time	Ordered Set	Rate	Type	Symbol	Character Symbol	Character KCode	Data (hex)	Data (binary)	Descrambled (hex)
104015	16.26n			Control	0000 0000			00h	00000000b	---

Bus Setup

Bus: B1

Bus Type: Serial

Bus 1: On

Clear Bus

Label: B1

Bus1 Position: 0.0div

Bus Type: Parallel

Auto

Input: Ch1

Threshold: 0.0V

Hysteresis: 50.0mV

Custom

8 Gb/s

Bus Setup

Bus: B1

Display Setup for: B1

Busform Decode

Symbol

Character Symbol

Character KCode

Data Hex

Data Binary

Descrambled Hex

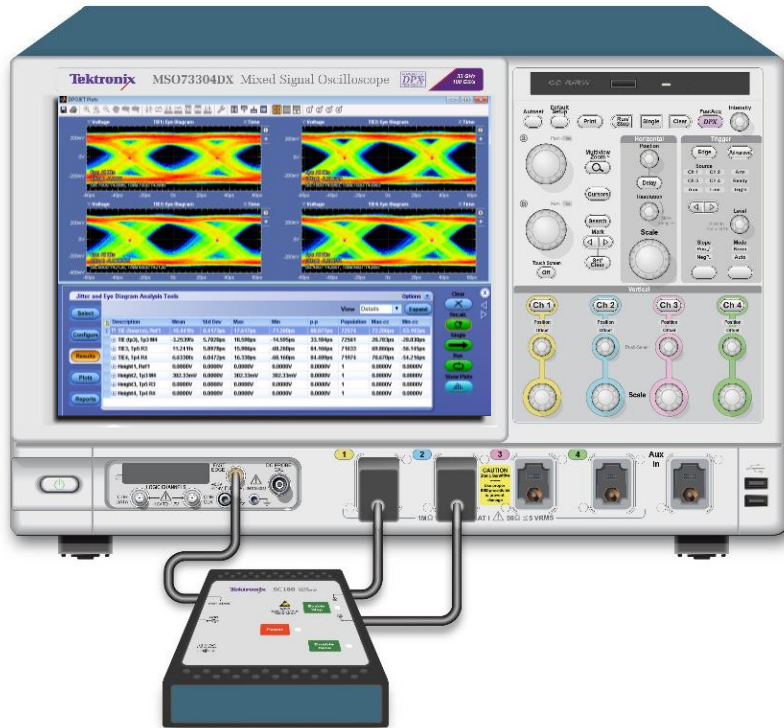
Descrambled Binary

Results Table

Off

Export

Channel Loss Characterization and De-embedding



Tektronix SignalCorrect™

1 Overview 2 Connect TCS and Scope 3 Select Interconnect 4 Select Calibration Source 5 Calibration 6 Measure Insertion Loss 7 Design Filter and Apply

Step 1: Overview

Signal Correct quickly characterizes interconnect effects and removes them from the acquired waveform without the need of a VNA.

First, a baseline calibration of the Tektronix Calibration Source is taken; alternatively factory settings can be used.

Next, the interconnect is measured and a filter is created representing the correction factor to apply to the acquired waveform. This filter can be used directly or saved for use at a later time.

Measure and Correct

Next > Exit

SignalCorrect: an easy to use solution that enables you to quickly characterize and de-embed the interconnect under test for more accurate measurement and analysis at much lower cost.



Tektronix Rx Test Solution



Introducing the BSX240 BERTScope

Key Elements in a PCIe Rx/Tx Link

Editor - Version: 1.7.109.0 Teclonix

File Edit Help

Capture/Length/Ampl - New PCIe_GEN_4.pcap

Encoding: PCI-E gen 4

Block Type: Standard SKP Ordered Set

Testpat	Name	Payload	Block Permissions
1	IEEECS Ordered Set	00 00 FF FF 00 00 FF FF 00 00 FF FF 00 00 FF FF	Static
2	TSL Ordered Set	1E 00 00 FF 0E 00 00 00 00 00 4A 4A 4A 4A 4A 4A	Partially Static
3	Standard SKP Ordered Set	AA AA AA AA AA AA AA AA AA AA AA AA E1 00 00 00	Static

CONFIGURE FIR FIL

STRESSED EYE

dB Bit Amplitudes

Single run completed

Equalizer: CTLE

CTLE Type: PCIe Gen 4

Auto

Equalizer: FFE / DFE

Adapt Taps: NRZ

Run Eq

Output

Results

Plot

Pre-DFE

OK

PCIe4AdaptationEQ.txt - Notepad

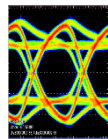
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# PCIe4 equalizer adaptation results
# Time: 16-Jun-2016 16:47:49

# CTLE(dB), CTLE(1in), DFE Tap(mv), DFE Tap(mv), Eye Area(UI*mv), Eye Height(mv), Eye width(UI), fz(GHz) fp1(GHz) fp2(GHz)
-6      0.501      29.98      14.58      6.01      18.45      0.33      4.00      4.00      16.00
-7      0.447      29.96      12.70      12.85      29.32      0.44      1.79      4.00      16.00
-8      0.398      29.23      10.18      19.28      37.57      0.51      1.59      4.00      16.00
-9      0.355      26.77      7.70      25.93      44.38      0.58      1.42      4.00      16.00
-10     0.316      24.46      5.87      31.87      50.50      0.63      1.26      4.00      16.00
-11***  0.282      19.32      3.42      33.68      52.03      0.65      1.13      4.00      16.00
-12     0.251      18.65      0.76      32.88      50.37      0.65      1.00      4.00      16.00
    
```



New BSX BERTScope with TXEQ, stress impairment, link training/handshaking

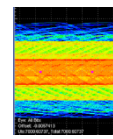


16GT/s



>20dB loss

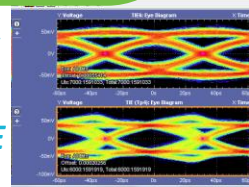
Channel Crosstalk/ISI



70K SX Scope with CDR + CTLE + DFE + Embed/De-Embed

CTLE ONLY

CTLE + DFE



Optimize Calibrate Automate

Debugging Loopback and Link Training

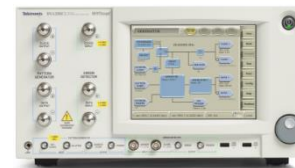
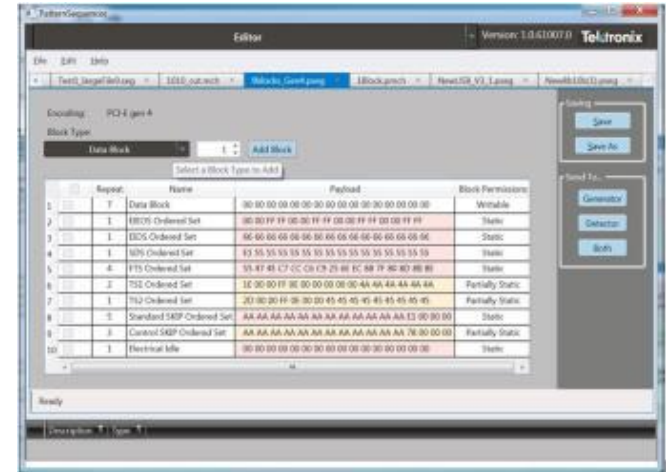
FROM COMPLEXITY TO CONFIDENCE

- **User Challenges:**

- Preparing receiver for test: **reliably putting device under test into loopback mode and completing link equalization training to optimize the channel**
- Debugging loopback and equalization failures

- **BSX Series BERTScope provides:**

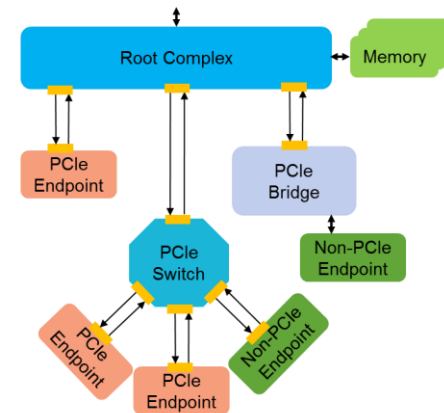
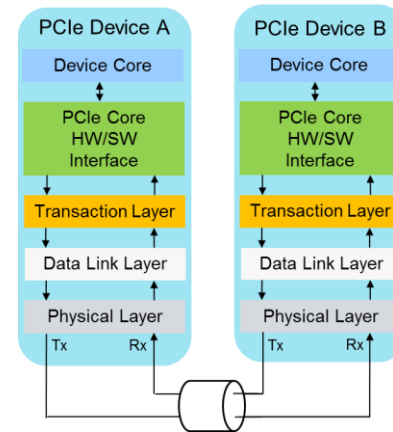
- Compliant link equalization training for PCIe Gen3 and Gen4
 - Fast internal control bus supports **500nS link training response time**
- Handshaking support above 16Gb/s
- Auto tuning and optimizing RxEQ settings via BER map



Debugging Loopback and Link Training

FROM COMPLEXITY TO CONFIDENCE

- Goal: Allow users to create their own **protocol-based patterns and link state traversals via stimulus-response feedback (protocol handshaking)**
- BSX Key Features:
 - Bit-oriented and protocol-oriented memory sequencer
 - Supports up to **128 states** and two levels of loop nesting
 - Sequence advancement by SW control, external signal, or Detector pattern match
 - Real-time data processing at **32 Gb/s**
 - Enhanced pattern/sequence editor
 - Stimulus-response feedback (handshaking)
 - Detector protocol pattern match -> Generator sequence advancement
 - Detector can match up to 16 user defined blocks
 - Up to 128 bits/block
 - Stimulus/response trigger output allows **cross-triggering of scope**



Debugging Loopback and Link Training

FROM COMPLEXITY TO CONFIDENCE

Initiate Loopback

Step	Status
Set Preshoot/Deemphasis	Setting PE to 3.50dB, and DE to -6.00dB ok
Clear Stresses	Clear Stresses ok
Configure Loopback	Configure Loopback ok
Load Sequence	Loaded sequence ok
Init Loopback	Loopback ok
Validate Loopback	Reports ok
Check Detector Clock	Detector clock is ok
Autoalign Detector	Detector Autoalign ok
Check Detector Sync	Detector sync is ok
Success	DUT is in Loopback mode

Initiate Loopback

Req#	Preset	Pre-cursor	Cursor	Post-cursor	Valid
28	0x9	0x36	0x0	x	
29	0x8	0x37	0x0	x	
30	0x9	0x36	0x0	x	
31	0x8	0x37	0x0	x	
32	0x9	0x36	0x0	x	
33	0x8	0x37	0x0	x	
34	0x7	0x38	0x0	x	
35	0x8	0x37	0x0	x	
36	0x7	0x38	0x0	x	
37	0x8	0x37	0x0	x	
38	0x9	0x36	0x0	x	
39	0x8	0x37	0x0	x	
40	0x9	0x36	0x0	x	
41	0x8	0x37	0x0	x	
42	0x9	0x36	0x0	x	
43	0x8	0x37	0x0	x	
44	0x9	0x36	0x0	x	
45	0x8	0x37	0x0	x	
46	0x9	0x36	0x0	x	
47	0x8	0x37	0x0	x	
48	0x9	0x36	0x0	x	
49	0x8	0x37	0x0	x	

DETECTOR

8,000.00 Mbit/s

DETECTOR RESULTS

Bits	23,228,775,040
Errors	0
BER	0.00E+00
Resyncs	0
Elapsed Time	00:00:04
Error Free	2.32E+10, 00:00:04

Sequencer Loaded for PCIe Loopback Initiation and Debug

50 iterative requests from the DUT for TXEQ tuning

Error Free Operation Achieved!

Debugging Rx BER Failures

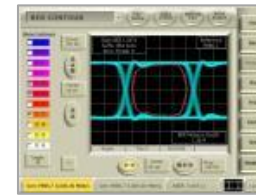
FROM COMPLEXITY TO CONFIDENCE

- **User Challenge:**

- Need more than a bit-error rate (BER) number
- Need to understand factors leading to bit error problems in order to debug issues

- **BSX Series BERTScope provides:**

- “Scope” functionality that complement those of the Tektronix scopes
- Full-featured and easy to use analysis tools
- Eye diagram for quick diagnosis of synchronization and BER failure issues
- Debug challenging signal integrity problems
 - Error Location Analysis
 - Pattern Capture
 - Jitter Map
 - BER Contour
 - FEC Emulation



BER Contour



Eye Diagram



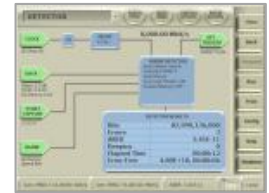
Error Location Correlation



FEC Emulation



Jitter Map



BER



Jitter



Jitter Tolerance

Tektronix Storage Test Solutions

FROM COMPLEXITY TO CONFIDENCE

Requires
Protocol
Awareness

Only with Tek...

...can you observe and debug protocol handshaking using a BERT at speeds up to 32Gb/s

Need
Automated
Solutions for
Gen3 and Gen4
Standards

...can you perform PCIe4 and SAS4 RX in-band testing using a single BERT
...can you automatically optimize CTLE/DFE settings
...can you fully automate PCIe compliance testing, reducing test time by over 2x

Go Beyond
Compliance

...can you obtain Rx failure insight using BERT error location analysis
...can you use an Rx pattern sequencer to customize approaches for loopback initiation and link training
...can you quickly characterize channel insertion loss and de-embed its effects



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